

## **Ultra Low Quiescent Current LDO Regulator**

#### **Features**

- Ultra Low 20 nA (typical) Quiescent Current
- Ultra Low Shutdown Supply Current: 0.1 nA (typical)
- 200 mA Output Current Capability for  $V_R \leq 3.5V$
- 100 mA Output Current Capability for  $V_R > 3.5V$
- Input Operating Voltage Range: 2.5V to 5.5V
- Standard Output Voltages ( $V_R$ ):
	- 1.2V, 1.5V, 1.8V, 2.0V, 2.5V, 3.0V, 3.3V, 4.2V
- Low Dropout Voltage: 450 mV Maximum at 200 mA
- Stable with 1.0 µF Ceramic Output Capacitor
- Overcurrent Protection
- Space-Saving, 8-Lead Plastic 2 x 2 VDFN

#### **Applications**

- Energy Harvesting
- Long Life Battery-Powered Applications
- Smart Cards
- Ultra Low Consumption "Green" Products
- Portable Electronics

#### **Description**

The MCP1710 is a 200 mA for  $V_R \le 3.5V$ , 100 mA for  $V_R > 3.5V$ , Low Dropout (LDO) linear regulator that provides high-current and low-output voltages, while maintaining an ultra low 20 nA of quiescent current during device operation. In addition, the MCP1710 can be shut down for an even lower 0.1 nA (typical) supply current draw. The MCP1710 comes in eight standard, fixed output voltage versions: 1.2V, 1.5V, 1.8V, 2V, 2.5V, 3V, 3.3V and 4.2V. The 200 mA output current capability, combined with the low-output voltage capability, make the MCP1710 a good choice for new ultra long life LDO applications that have high-current demands, but require ultra low-power consumption during Sleep states.

The MCP1710 is stable using ceramic output capacitors that inherently provide lower output noise, and reduce the size and cost of the entire regulator solution. Only 1  $\mu$ F (2.2  $\mu$ F recommended) of output capacitance is needed to stabilize the LDO.

The MCP1710 device's ultra low quiescent and shutdown current allows it to be paired with other ultra low-current draw devices, such as Microchip's XLP technology devices, for a complete ultra low-power solution.

#### <span id="page-0-0"></span>**Package Type**



## **Typical Application**



## **Functional Block Diagram**



## <span id="page-2-5"></span>**1.0 ELECTRICAL CHARACTERISTICS**

## **Absolute Maximum Ratings<sup>+</sup>**



<span id="page-2-3"></span><sup>t</sup> Notice: Stresses above those listed under "Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at those or any other conditions above those indicated in the operational listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

## <span id="page-2-6"></span>**AC/DC CHARACTERISTICS**

**Electrical Specifications:** Unless otherwise noted, V<sub>IN</sub> = V<sub>R</sub> + 800 mV [\(Note 1\)](#page-2-0),  $I_{\text{OUT}}$  = 1 mA, C<sub>IN</sub> = C<sub>OUT</sub> = 2.2 µF (X7R Ceramic),  $T_A = +25^{\circ}$ C. **Boldface** type applies for junction temperatures  $T_J$  of -40°C to +85°C ([Note 4](#page-2-1)). Parameters **Nigal Example 1 Sym.** Min. Typ. Max. Units Conditions Input Operating Voltage  $V_{\text{IN}}$  **2.7**  $-$  **5.5** V **2.5**  $\vert$  - **5.5**  $\vert$  V  $\vert$  V<sub>R</sub> < 2.5V Output Voltage Range  $V_{\text{OUT}}$  **1.2**  $-$  **4.2** V Input Quiescent Current  $\begin{vmatrix} 1 & 0 \\ 0 & 1 \end{vmatrix}$   $\begin{vmatrix} 20 & 20 \\ -1 & 20 \end{vmatrix}$   $\begin{vmatrix} 1 & 0 \\ -1 & 0 \end{vmatrix}$  nA  $\begin{vmatrix} V_{1N} = 2.5V \text{ to } 5.5V,$  $I_{OUT} = 0$ Input Quiescent Current for SHDN Mode  $I_{\overline{\text{SHDN}}}$   $0.1$   $1$  nA  $\overline{\text{SHDN}}$  = GND Maximum Continuous Output Current  $I_{\text{OUT}}$   $\vert$   $\vert$   $\vert$   $-$  **200** | mA |  $V_{\text{R}}$  ≤ 3.5V  $100$   $mA$   $V_R > 3.5V$ Current Limit IOUT ó 250 ó mA VOUT = 0.9 x VR,  $V_R \leq 3.5V$  $-$  175  $-$  mA  $V_{\text{OUT}} = 0.9 \times V_{\text{R}}$ ,  $V_R > 3.5V$ Output Voltage Regulation VOUT **V<sup>R</sup> ñ 4%** ó **V<sup>R</sup> + 4%** V V<sup>R</sup> < 1.8V **([Note 2](#page-2-2))**  $V_R - 2\%$  │  $\rightarrow$  │ $V_R + 2\%$ │  $\quadvee$  │ $V_R$ ≥ 1.8V ([Note 2](#page-2-2)) Line Regulation  $\Delta V_{\text{OUT}}/$  $(V_{OUT} \times \Delta V_{IN})$ 0.5 **4** %  $V_{\text{IN}} = V_{\text{IN(Min)}}$  to 5.5V,  $V_R \ge 1.8V$ ,  $V_{OUT} = 50$  mA **([Note 1](#page-2-0))** ó ó **4** % VIN = VIN(Min) to 5.5V, V<sub>R</sub> < 1.8V, I<sub>OUT</sub> = 50 mA **([Note 1](#page-2-0))**

<span id="page-2-4"></span><span id="page-2-2"></span><span id="page-2-0"></span>**Note 1:** The minimum  $V_{IN}$  must meet two conditions:  $V_{IN} \geq V_{IN(Min)}$  and  $V_{IN} \geq V_R + V_{DROPOUT(Max)}$ .

**2:**  $V_R$  is the nominal regulator output voltage.  $V_R = 1.2V$ ,  $2.5V$ , etc.

**3:** Dropout voltage is defined as the input-to-output voltage differential at which the output voltage drops 3% below its nominal value that was measured with an input voltage of  $V_{\text{IN}} = V_{\text{OUT(Max)}} + V_{\text{DROPOUT(Max)}}$ .

<span id="page-2-1"></span>**4:** The junction temperature is approximated by soaking the device under test at an ambient temperature equal to the desired junction temperature. The test time is small enough such that the rise in the junction temperature over the ambient temperature is not significant.

Rejection Ratio

## **AC/DC CHARACTERISTICS (CONTINUED)**

Load Regulation  $\Delta V_{\text{OUT}}|_{\text{OUT}}|_{\text{OUT}}|_{\text{IV}}$  1 | 3 | %  $\Delta V_{\text{INI}}|_{\text{IV}}$  = (V<sub>IN(Min)</sub> + V<sub>IN(Max)</sub>)/2,  $I_{\text{OUT}} = 0.02 \text{ m/A}$  to 200 mA **([Note 1](#page-2-0))** Dropout Voltage  $V_{\text{DROPOUT}}$   $450$  mV  $I_{\text{OUT}}$  = 200 mA,  $V_R \leq 3.5V$  (**Note 3**) **400** mV  $|I_{\text{OUT}}| = 100 \text{ mA}$ , V<sup>R</sup> > 3.5V (**[Note 3](#page-2-4)) Shutdown Input** Logic High Input  $V_{\text{SHDN-HIGH}}$  **70**  $\vert$   $\vert$   $\vert$   $\%V_{\text{IN}}$   $\vert$   $V_{\text{IN}}$  =  $V_{\text{IN(Min)}}$  to 5.5V **[\(Note 1\)](#page-2-0)** Logic Low Input  $V_{\text{SHDN-LOW}}$   $\vert$   $\vert$   $\vert$  30  $\vert$  %V<sub>IN</sub>  $\vert$ V<sub>IN</sub> = V<sub>IN(Min)</sub> to 5.5V [\(Note 1\)](#page-2-0) **AC Performance** Output Delay From  $\overline{SHDN}$   $T_{OR}$   $30$   $\overline{SHDN}$  = GND to V<sub>IN</sub>,  $V_{OUT}$  = GND to 95%  $V_R$ Output Noise  $\begin{vmatrix} e_N & | & - \ 0.37 & | & - \end{vmatrix}$   $\begin{vmatrix} 0.17 & | & 0 \end{vmatrix}$   $\begin{vmatrix} 0.17 & | & 50 \end{vmatrix}$  mA, f = 1 kHz,  $C<sub>OUT</sub> = 2.2 \mu F (X7R Ceramic),$  $V_R = 2.5V$ Power Supply Ripple PSRR  $\vert$  -  $\vert$  22  $\vert$  -  $\vert$  dB  $\vert$  f = 100 Hz, I<sub>OUT</sub> = 10 mA, **Electrical Specifications:** Unless otherwise noted,  $V_{IN} = V_R + 800$  mV **(Note 1)**,  $I_{OUT} = 1$  mA,  $C_{IN} = C_{OUT} = 2.2$  µF (X7R Ceramic),  $T_A = +25^{\circ}$ C. **Boldface** type applies for junction temperatures  $T_A$  of **-40°C to +85°C** (Note 4). Parameters | Sym. | Min. | Typ. | Max. | Units | Conditions

**Note 1:** The minimum V<sub>IN</sub> must meet two conditions:  $V_{IN} \geq V_{IN(Min)}$  and  $V_{IN} \geq V_R + V_{DROPOUT(Max)}$ .

**2:**  $V_R$  is the nominal regulator output voltage.  $V_R = 1.2V$ , 2.5V, etc.

**3:** Dropout voltage is defined as the input-to-output voltage differential at which the output voltage drops 3% below its nominal value that was measured with an input voltage of  $V_{IN} = V_{OUT(Max)} + V_{DROPOUT(Max)}$ .

**4:** The junction temperature is approximated by soaking the device under test at an ambient temperature equal to the desired junction temperature. The test time is small enough such that the rise in the junction temperature over the ambient temperature is not significant.

## **TEMPERATURE SPECIFICATIONS**

**Electrical Specifications:** Unless otherwise noted,  $V_{IN} = V_R + 800$  mV, ([Note 1](#page-2-0)),  $I_{OUT} = 1$  mA,  $C_{IN} = C_{OUT} = 2.2 \mu F$ (X7R Ceramic),  $T_A$  = +25°C. **Boldface** type applies for junction temperatures,  $T_J$  of -40°C to +85°C ([Note 4\)](#page-2-1)



 $V_{INAC}$  = 200 mV pk-pk,

 $C_{IN} = 0 \mu F$ 

## **2.0 TYPICAL PERFORMANCE CURVES**

**Note:** The graphs and tables provided following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs or tables, the data presented may be outside the specified operating range (e.g., outside specified power supply range) and therefore outside the warranted range.

**Note:** Unless otherwise indicated, C<sub>OUT</sub> = 2.2 µF Ceramic (X7R), C<sub>IN</sub> = 2.2 µF Ceramic (X7R), I<sub>OUT</sub> = 1 mA, Temperature = +25°C,  $V_{IN} = V_R + 0.8V$ ,  $\overline{SHDN} = 1 M\Omega$  pull-up to  $V_{IN}$ .



*FIGURE 2-1: Output Voltage vs. Input Voltage (V<sup>R</sup> = 1.2V).*



*FIGURE 2-2: Output Voltage vs. Input Voltage (V<sub>R</sub> = 2.5V).* 



*FIGURE 2-3: Output Voltage vs. Input Voltage (V<sub>R</sub> = 4.2V).* 



*FIGURE 2-4: Output Voltage vs. Load Current (V<sup>R</sup> = 1.2V).*



*FIGURE 2-5: Output Voltage vs. Load Current (V<sub>R</sub> = 2.5V).* 



*FIGURE 2-6: Output Voltage vs. Load Current* ( $V_R$  = 4.2V).

**Note:** Unless otherwise indicated,  $C_{OUT}$  = 2.2 µF Ceramic (X7R),  $C_{IN}$  = 2.2 µF Ceramic (X7R),  $I_{OUT}$  = 1 mA, Temperature = +25°C,  $V_{IN} = V_R + 0.8V$ ,  $\overline{SHDN} = 1 M\Omega$  pull-up to  $V_{IN}$ .



*FIGURE 2-7: Dropout Voltage vs. Load Current (V<sub>R</sub> = 2.5V).* 



*FIGURE 2-8: Dropout Voltage vs. Load Current (V<sub>R</sub> = 4.2V).* 





*FIGURE 2-10: Power Supply Ripple Rejection vs. Frequency (* $V_R$  *= 1.2V).* 



*FIGURE 2-11: Power Supply Ripple Rejection vs. Frequency (V<sub>R</sub> = 2.5V).* 



*FIGURE 2-12: Power Supply Ripple Rejection vs. Frequency (* $V_R$  *= 4.2V).* 

**Note:** Unless otherwise indicated, C<sub>OUT</sub> = 2.2 µF Ceramic (X7R), C<sub>IN</sub> = 2.2 µF Ceramic (X7R), I<sub>OUT</sub> = 1 mA, Temperature = +25°C,  $V_{IN} = V_R + 0.8V$ ,  $\overline{SHDN} = 1$  M $\Omega$  pull-up to  $V_{IN}$ .



<span id="page-6-0"></span>*FIGURE 2-13: Dynamic Load Step*   $(V_R = 1.2V)$ .



*FIGURE 2-14: Dynamic Load Step*   $(V_R = 2.5V)$ .



 $(V_R = 4.2V)$ .



*FIGURE 2-16: Dynamic Line Step*   $(V_R = 1.2V)$ .



*FIGURE 2-17: Dynamic Line Step*   $(V_R = 2.5V)$ .



*FIGURE 2-18: Dynamic Line Step*   $(V_R = 4.2V)$ .

**Note:** Unless otherwise indicated,  $C_{OUT}$  = 2.2 µF Ceramic (X7R),  $C_{IN}$  = 2.2 µF Ceramic (X7R),  $I_{OUT}$  = 1 mA, Temperature = +25°C,  $V_{1N}$  =  $V_R$  + 0.8V, SHDN = 1 M $\Omega$  pull-up to  $V_{1N}$ .











*FIGURE 2-21: Start-up from VIN*  $(V_R = 4.2V)$ .

**LeGas**  $I_{\text{OUT}} = 10 \text{ mA}$ **SHDN Signal**  $V_{\text{OUT}} = 1.2V$ **5 ms/div 2V/div – 1V/div** 

*FIGURE 2-22: Start-up from SHDN*  $(V_R = 1.2V)$ .



*FIGURE 2-23: Start-up from SHDN*  $(V_R = 2.5V)$ .



<span id="page-7-0"></span>*FIGURE 2-24: Start-up from SHDN*  $(V_R = 4.2V)$ .









*FIGURE 2-26: Load Regulation vs. Junction Temperature (V<sub>R</sub> = 2.5V).* 



*FIGURE 2-27: Load Regulation vs. Junction Temperature (V<sub>R</sub> = 4.2V).* 



*FIGURE 2-28: Line Regulation vs. Junction Temperature.*



*FIGURE 2-29: Quiescent Current vs. Input Voltage.*



*FIGURE 2-30: Ground Current vs. Junction Temperature.*

**Note:** Unless otherwise indicated, C<sub>OUT</sub> = 2.2 µF Ceramic (X7R), C<sub>IN</sub> = 2.2 µF Ceramic (X7R), I<sub>OUT</sub> = 1 mA, Temperature = +25°C,  $V_{IN}$  =  $V_R$  + 0.8V, SHDN = 1 M $\Omega$  pull-up to  $V_{IN}$ .



*FIGURE 2-31: Ground Current vs. Load Current.*

## <span id="page-10-1"></span>**3.0 PIN DESCRIPTION**

The descriptions of the pins are listed in [Table 3-1.](#page-10-0)



<span id="page-10-0"></span>

#### **3.1 Ground Pin (GND)**

For optimal noise and Power Supply Rejection Ratio (PSRR) performance, the GND pin of the LDO should be tied to an electrically quiet circuit ground. This will help the LDO Power Supply Rejection Ratio and noise performance. The GND pin of the LDO only conducts the ground current, so a heavy trace is not required. For applications that have switching or noisy inputs, tie the GND pin to the return of the output capacitor. Ground planes help lower the inductance and voltage spikes caused by fast transient load currents.

#### **3.2 Regulated Output Voltage Pin (VOUT)**

The  $V_{\text{OUT}}$  pin is the regulated output voltage of the LDO. A minimum output capacitance of 1.0 µF is required for LDO stability. The MCP1710 is stable with ceramic, tantalum and aluminum-electrolytic capacitors. See **Section 4.2 "Output Capacitor"** for output capacitor selection guidance.

### **3.3 Feedback Pin (FB)**

The output voltage is connected to the FB input. This sets the output voltage regulation value.

## **3.4 Input Voltage Supply Pin (VIN)**

Connect the unregulated or regulated input voltage source to  $V_{IN}$ . If the input voltage source is located several inches away from the LDO, or the input source is a battery, it is recommended that an input capacitor be used. A typical input capacitance value of 1 µF to 10 µF should be sufficient for most applications (2.2 µF, typical). The type of capacitor used can be ceramic, tantalum, or aluminum-electrolytic. The low-ESR characteristics of the ceramic capacitor will yield better noise and PSRR performance at high frequency.

## **3.5 Shutdown Control Input (SHDN)**

The SHDN input is used to turn the LDO output voltage on and off. When the SHDN input is at a logic high level, the LDO output voltage is enabled. When the SHDN input is pulled to a logic low level, the LDO output voltage is disabled. When the SHDN input is pulled low, the LDO enters a low quiescent current shutdown state, where the typical quiescent current is 0.1 nA.

### **3.6 Exposed Thermal Pad (EP)**

The VDFN-8 package has an exposed thermal pad on the bottom of the package. The exposed thermal pad gives the device better thermal characteristics by providing a good thermal path to either the Printed Circuit Board (PCB), or heat sink, to remove heat from the device. The exposed pad of the package is at ground potential.

**NOTES:**

## **4.0 DEVICE OVERVIEW**

The MCP1710 is a 100 mA/200 mA output current, Low Dropout (LDO) voltage regulator. The Low Dropout voltage of 450 mV maximum, at 200 mA of current, makes it ideal for battery-powered applications. The input voltage ranges from 2.5V to 5.5V. The MCP1710 adds a shutdown control input pin. The MCP1710 is available in eight standard fixed output voltage options: 1.2V, 1.5V, 1.8V, 2V, 2.5V, 3.0V, 3.3V and 4.2V. The MCP1710 uses a proprietary voltage reference and sensing scheme to maintain the ultra low 20 nA quiescent current.

#### **4.1 Output Current and Current Limiting**

The MCP1710 LDO is tested and ensured to supply a minimum of 200 mA of output current for the 1.2V to 3.5V output range, and 100 mA of output current for the 3.5V to 4.2V output range. The MCP1710 has no minimum output load, so the output load current can go to 0 mA and the LDO will continue to regulate the output voltage within the specified tolerance.

The MCP1710 also incorporates an output current limit. The current limit is set to 250 mA, typical, for the  $1.2V \le V_R \le 3.5V$  range, and 175 mA, typical, for the  $3.5V < V_R \leq 5.5V$  range.

#### <span id="page-12-0"></span>**4.2 Output Capacitor**

The MCP1710 requires a minimum output capacitance of 1 µF for output voltage stability. Ceramic capacitors are recommended because of their size, cost and robust environmental qualities.

Aluminum-electrolytic and tantalum capacitors can be used on the LDO output as well. The output capacitor should be located as close to the LDO output as is practical. Ceramic materials, X7R and X5R, have low-temperature coefficients and are well within the acceptable ESR range required. A typical 1 µF X7R 0805 capacitor has an ESR of 50 m $\Omega$ .

### **4.3 Input Capacitor**

Low input source impedance is necessary for the LDO output to operate properly. When operating from batteries, or in applications with long lead length (>10 inches) between the input source and the LDO, some input capacitance is recommended. A minimum of 1.0 µF to 4.7 µF is recommended for most applications.

For applications that have output step load requirements, the input capacitance of the LDO is very important. The input capacitance provides a low-impedance source of current for the LDO to use for dynamic load changes. This allows the LDO to respond quickly to the output load step. For good step response performance, the input capacitor should be of equivalent or higher value than the output capacitor. The

capacitor should be placed as close to the input of the LDO as is practical. Larger input capacitors will also help reduce any high-frequency noise on the input and output of the LDO, as well as the effects of any inductance that exists between the input source voltage and the input capacitance of the LDO.

## **4.4 Shutdown Input (SHDN)**

The SHDN input is an active-low input signal that turns the LDO on and off. The SHDN threshold is a percentage of the input voltage. The maximum input low logic level is 30% of  $V_{IN}$  and the minimum high logic level is  $70\%$  of  $V_{IN}$ .

On the rising edge of the SHDN input, the shutdown circuitry has a 30 ms (typical) delay before allowing the LDO output to turn on. This delay helps to reject any false turn-on signal or noise on the SHDN input signal. After the 30 ms delay, the LDO output enters its current-limited soft start period as it rises from 0V to its final regulation value. If the SHDN input signal is pulled low during the 30 ms delay period, the timer will be reset and the delay time will start over again on the next rising edge of the SHDN input. The total time from the SHDN input going high (turn on) to the LDO output being in regulation is typically 30 ms. See [Figure 4-1](#page-12-1) for a timing diagram of the SHDN input.



## <span id="page-12-1"></span>**4.5 Dropout Voltage**

Dropout voltage is defined as the input-to-output voltage differential at which the output voltage drops 3% below the nominal value that was measured with a  $V_R$  + 0.8V differential applied. The MCP1710 LDO has a Low Dropout voltage specification of 450 mV for the  $1.2V \le V_R \le 3.5V$  range (typical) at 200 mA out, and 400 mV for the  $3.5V < V_R \le 5.5V$  range (typical) at 100 mA out. See Section 1.0 "Electrical **Section 1.0 Characteristics**" for maximum dropout voltage specifications.

**NOTES:**

### **5.0 APPLICATION CIRCUITS/ISSUES**

#### **5.1 Typical Application**

The MCP1710 is used for applications that require ultra low quiescent current draw.





*FIGURE 5-1: Typical Application Circuit.*

#### **5.2 Power Calculations**

#### 5.2.1 POWER DISSIPATION

The internal power dissipation within the MCP1710 is a function of input voltage, output voltage, output current and quiescent current. [Equation 5-1](#page-14-1) can be used to calculate the internal power dissipation for the LDO.

#### <span id="page-14-1"></span>**EQUATION 5-1:**

$$
P_{LDO} = (V_{IN(MAX)} - V_{OUT(MIN)}) \times I_{OUT(MAX)}
$$
  
Where:  

$$
P_{LDO} = \text{Internal power dissipation of theLDO pass device}
$$
  

$$
V_{IN(MAX)} = \text{Maximum input voltage}
$$
  

$$
V_{OUT(MIN)} = \text{LDO minimum output voltage}
$$
  

$$
I_{OUT(MAX)} = \text{Maximum output current}
$$

In addition to the LDO pass element power dissipation, there is power dissipation within the MCP1710 as a result of quiescent or ground current. The power dissipation as a result of the ground current can be calculated using [Equation 5-2:](#page-14-0)

#### <span id="page-14-0"></span>**EQUATION 5-2:**

$$
P_{I(GND)} = V_{IN(MAX)} \times I_{GND}
$$
  
Where:  

$$
P_{I(GND)} = Power \text{ dissipation due to the quiescent current of the LDO}
$$
  

$$
V_{IN(MAX)} = Maximum \text{ input voltage}
$$

$$
N(MAX) = MAXMH
$$
\n
$$
I_{GND} = Current flowing in the GND pin
$$

The total power dissipated within the MCP1710 is the sum of the power dissipated in the LDO pass device and the  $P(I_{GND})$  term. Because of the CMOS construction, the typical  $I_{GND}$  for the MCP1710 is 200  $\mu$ A at full load. Operating at a maximum V<sub>IN</sub> of 5.5V results in a power dissipation of 1.1 mW. For most applications, this is small compared to the LDO pass device power dissipation and can be neglected.

The maximum continuous operating junction temperature specified for the MCP1710 is +85°C. To estimate the internal junction temperature of the MCP1710, the total internal power dissipation is multiplied by the thermal resistance from junction-to-ambient ( $R\theta_{IA}$ ) of the device. The thermal resistance from junction-to-ambient for the 2 x 2 VDFN-8 package is estimated at 73.1°C/W.

#### **EQUATION 5-3:**

$$
T_{J(MAX)} = P_{TOTAL} \times R \theta_{JA} + T_{A(MAX)}
$$

Where:

 $T_{J(MAX)}$  = Maximum continuous junction temperature

 $P_{\text{TOTAL}}$  = Total power dissipation of the device

- $R\theta_{JA}$  = Thermal resistance from junction to ambient
- $T_{A(MAX)}$  = Maximum ambient temperature

The maximum power dissipation capability for a package can be calculated given the junction-to-ambient thermal resistance and the maximum ambient temperature for the application. [Equation 5-4](#page-14-2) can be used to determine the package maximum internal power dissipation.

#### <span id="page-14-2"></span>**EQUATION 5-4:**

$$
P_{D(MAX)} = \frac{(T_{J(MAX)} - T_{A(MAX)})}{R \theta_{JA}}
$$

Where:

 $P_{D(MAX)}$  = Maximum power dissipation of the device

$$
T_{J(MAX)} = Maximum\text{ continuous junction}
$$
  
temperature

 $T_{A(MAX)}$  = Maximum ambient temperature

$$
R\theta_{JA}
$$
 = Thermal resistance from  
junction-to-ambient

#### **EQUATION 5-5:**

$$
T_{J(RISE)} = P_{D(MAX)} \times R \theta_{JA}
$$



#### **EQUATION 5-6:**

 $T_J = T_{J(RISE)} + T_A$ 

 $T_{\rm J}$  = Junction temperature

 $T_{J(RISE)}$  = Rise in the device's junction temperature over the ambient temperature

 $T_A$  = Ambient temperature

#### **5.3 Typical Application Examples**

Internal power dissipation, junction temperature rise, junction temperature and maximum power dissipation are calculated in the following example. The power dissipation, as a result of ground current, is small enough to be neglected.

#### 5.3.1 POWER DISSIPATION EXAMPLES

#### **EXAMPLE 5-1:**

**Package** Package Type = 2 x 2 VDFN-8

**Input Voltage**

 $V_{IN} = 3.3V \pm 5%$ 

**LDO Output Voltage and Current**

 $V_{OUT} = 2.5V$ 

$$
I_{\text{OUT}} = 200 \text{ mA}
$$

**Maximum Ambient Temperature**

 $T_{A(MAX)} = +60^{\circ}C$ 

#### **Internal Power Dissipation**

 $P_{LDO(MAX)} = (V_{IN(MAX)} - V_{OUT(MIN)})$  x  $I_{OUT(MAX)}$  $P_{LDO}$  = ((3.3V x 1.05) – (2.5V x 0.975)) x 200 mA  $P_{LDO}$  = 0.206 Watts

#### 5.3.1.1 Device Junction Temperature Rise

The internal junction temperature rise is a function of internal power dissipation and the thermal resistance, from junction-to-ambient, for the application. The thermal resistance, from junction-to-ambient (R $\theta_{IA}$ ), is derived from the EIA/JEDEC standards for measuring thermal resistance. The EIA/JEDEC specification is JESD51. The standard describes the test method and board specifications for measuring the thermal resistance from junction-to-ambient. The actual thermal resistance for a particular application can vary depending on many factors, such as copper area and thickness. Refer to AN792, *ìA Method to Determine How Much Power a SOT23 Can Dissipate in an Applicationî* (DS00792), for more information regarding this subject.

#### **EXAMPLE 5-2:**

$$
T_{J(RISE)} = P_{\text{TOTAL}} \times R\theta_{JA}
$$
  
\n
$$
T_{J(RISE)} = 0.206 \text{W} \times 73.1^{\circ} \text{C/W}
$$
  
\n
$$
T_{J(RISE)} = 15.1^{\circ} \text{C}
$$

#### 5.3.1.2 Junction Temperature Estimate

To estimate the internal junction temperature, the calculated temperature rise is added to the ambient or offset temperature. For this example, the worst-case junction temperature is estimated below:

#### **EXAMPLE 5-3:**

$$
T_J = T_{J(RISE)} + T_{A(MAX)}
$$
  
 $T = 45.4$ °C + 69.0°C

 $T_J$  = 15.1°C + 60.0°C  $T_{J}$  = 75.1°C

5.3.1.3 Maximum Package Power Dissipation at +60°C Ambient **Temperature** 

#### **EXAMPLE 5-4:**

**2x2 VDFN-8 (73.1°C/W RJA):**

 $P_{D(MAX)} = (85^{\circ}C - 60^{\circ}C)/73.1^{\circ}C/W$ 

 $P_{D(MAX)} = 0.342W$ 

## <span id="page-16-0"></span>**6.0 PACKAGING INFORMATION**

## **6.1 Package Marking Information**

8-Lead VDFN (2 x 2 x 0.9) Example









### 8- Lead Very Thin Dual Flatpack No-Lead (LZ) - 2x2x0.9 mm Body [VDFN]

For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging **Note:** 



Microchip Technology Drawing C04-198B Sheet 1 of 2

#### 8- Lead Very Thin Dual Flatpack No-Lead (LZ) - 2x2x0.9 mm Body [VDFN]

For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging **Note:** 





#### DETAIL B



#### **Notes:**

1. Pin 1 visual index feature may vary, but must be located within the hatched area.

2. Package may have one or more exposed tie bars at ends.

3. Package is saw singulated

3. Dimensioning and tolerancing per ASME Y14.5M.

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

REF: Reference Dimension, usually without tolerance, for information purposes only.

Microchip Technology Drawing C04-198B Sheet 2 of 2

#### **8-Lead Plastic Very Thin Flat, No Lead Package (LZ) - 2x2 mm Body [VDFN] With 0.55mm Contact Length**

For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging **Note:**



#### RECOMMENDED LAND PATTERN



#### Notes:

1. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing No. C04-2198A

## **APPENDIX A: REVISION HISTORY**

#### **Revision D (May 2015)**

- Changed minimum input voltage to 2.5V.
- **Updated the [Package Type](#page-0-0) figure.**
- ï Updated the **[AC/DC Characteristics](#page-2-6)** table.
- **Updated Section 3.0 "Pin Description".**

#### **Revision C (July 2014)**

The following is the list of modifications:

- 1. Added the information related to the 1.5V, 2V and 3V devices throughout the document.
- 2. Updated package markings and drawings in **Section 6.0 "Packaging Information".**
- 3. Minor typographical changes.

#### **Revision B (November 2012)**

• Updated the performance curves for Dynamic Load Step, Dynamic Line Step, Startup from  $V_{IN}$ , and Startup from SHDN ([Figure 2-13-](#page-6-0)[Figure 2-24\)](#page-7-0).

#### **Revision A (September 2012)**

• Original Release of this Document.

## **PRODUCT IDENTIFICATION SYSTEM**

To order or obtain information, e.g., on pricing or delivery, refer to the factory or the listed sales office.

<span id="page-21-0"></span>

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